

Total No. of Questions : 8]

SEAT No. :

P6613

[Total No. of Pages : 2

[6181]-176

B.E. (Electronics & Telecommunication Engineering)

VLSI DESIGN & TECHNOLOGY

(2019 Pattern) (Semester-VII) (404182)

Time : 2½ Hours]

[Max. Marks : 70

Instructions to the candidates:

- 1) Answer Q.1 or Q.2, Q.3 or Q.4, Q.5 or Q.6, Q.7 or Q.8.
- 2) Neat diagrams must be drawn wherever necessary.
- 3) Figures to the right indicate full marks.
- 4) Use of electronic pocket calculator is allowed.
- 5) Assume suitable data, if necessary.

Q1) a) Distinguish between FPGA and CPLD. [6]

b) Explain with diagram SRAM and Anti-fuse programming techniques used in FPGA? [6]

c) Write short note on VLSI Design flow with respect to PLDs. [6]

OR

Q2) a) Write short note on CPLD. [6]

b) Explain synthesis and simulation tools in brief. [6]

c) Give typical features and specifications of FPGA. [6]

Q3) a) Draw and explain CMOS Inverter transfer characteristics with all regions in detail. [7]

b) Draw CMOS logic for $Y = \overline{AB + CD + E}$. Calculate W/L ratio for NMOS and PMOS & area needed on the chip. [10]

OR

Q4) Write short note on:

a) Body effect. [4]

b) Channel length modulation. [4]

c) Draw NAND, NOR, AND, OR gates using CMOS. [9]

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- Q5)** a) Explain Antenna effect. [5]
b) Explain Electro migration effect in detail. [5]
c) Draw stick diagram of CMOS inverter, 2 input NAND and NOR gates. [8]

OR

- Q6)** a) Explain LAMBDA rules used for CMOS layout design. [6]
b) Write short note on Drain punch through. [6]
c) Write SPICE code for CMOS inverter for AC analysis. [6]

- Q7)** a) Write short note need of design for Testability & Adhoc DFT techniques. [8]
b) Explain stuck at fault models with suitable examples. [9]

OR

- Q8)** a) Write short note on BIST with block diagram. [8]
b) Explain JTAG boundary scan method for testing. [9]

